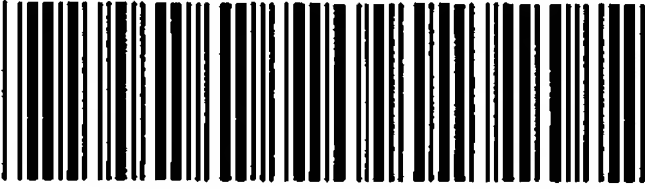


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/072,415	LEE ET AL.	
	Examiner	Art Unit	
	Steven J. Fulk	2891	

SEARCHED			
Class	Subclass	Date	Examiner
257	10	8/2/2006	SJF
438	20	8/2/2006	SJF
313	310	8/2/2006	SJF
313	309	8/2/2006	SJF
313	351	8/2/2006	SJF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR